

# SuperFET\*\*

# FCA20N60S / FCA20N60S\_F109

#### 600V N-Channel MOSFET

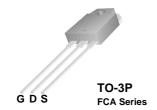
#### **Features**

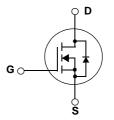
- 650V @T<sub>J</sub> = 150°C
- Typ. Rds(on)=0.22Ω
- Ultra low gate charge (typ. Qg=55nC)
- Low effective output capacitance (typ. Coss.eff=110pF)
- 100% avalanche tested

### **Description**

SuperFET<sup>TM</sup> is, Farichild's proprietary, new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance.

This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SuperFET is very suitable for various AC/DC power conversion in switching mode operation for system miniaturization and higher efficiency.





## **Absolute Maximum Ratings**

Symbol	Parameter		FCA20N60S	Unit
V <sub>DSS</sub>	Drain-Source Voltage		600	V
I <sub>D</sub>	Drain Current - Continuous - Continuous	$s (T_C = 25^{\circ}C)$ $s (T_C = 100^{\circ}C)$	20 12.7	A A
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	60	А
V <sub>GSS</sub>	Gate-Source voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		450	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	20	А
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	26	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C) - Derate abo	ve 25°C	260 2.1	W W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C

<sup>\*</sup>Drain current limited by maximum junction temperature

#### **Thermal Characteristics**

Symbol	Parameter	FCA20N60S	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.48	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	41.7	°C/W	

# **Package Marking and Ordering Information**

<b>Device Marking</b>	Device	Package	Reel Size	Tape Width	Quantity
FCA20N60S	FCA20N60S	TO-3P	-	-	30
FCA20N60S	FCA20N60S_F109	TO-3PN	-	-	30

# **Electrical Characteristics** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Conditions	Min	Тур	Max	Units
Off Charac	teristics			!	ļ	
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0V$ , $I_D = 250\mu A$ , $T_J = 25^{\circ}C$	600			V
		$V_{GS} = 0V$ , $I_D = 250\mu A$ , $T_J = 150^{\circ} C$		650		V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C		0.6		V/°C
BV <sub>DS</sub>	Drain-Source Avalanche Breakdown Voltage	$V_{GS} = 0V$ , $I_D = 20A$		700		V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 600V, V <sub>GS</sub> = 0V V <sub>DS</sub> = 480V, T <sub>C</sub> = 125°C			1 10	μ <b>Α</b> μ <b>Α</b>
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	$V_{GS} = 30V$ , $V_{DS} = 0V$			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30V$ , $V_{DS} = 0V$			-100	nA
On Charac	teristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$	3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 10A		0.22	0.26	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40V, I <sub>D</sub> = 10A (Note 4)		11.5		S
Dynamic C	haracteristics					_
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25V, V_{GS} = 0V,$		1730	2250	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0MHz		960	1150	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			85		pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 480V, V_{GS} = 0V, f = 1.0MHz$		45	60	pF
Coss eff.	Effective Output Capacitance	$V_{DS} = 0V$ to 400V, $V_{GS} = 0V$		110		pF
Switching	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 300V, I_D = 20A$		46	90	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25\Omega$		140	280	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			175	350	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		100	200	ns
$Q_g$	Total Gate Charge	$V_{DS} = 480V, I_{D} = 20A$		57	72	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = 10V		11.5	14	nC
$Q_{gd}$	Gate-Drain Charge	(Note 4, 5)		28		nC
Drain-Sour	ce Diode Characteristics and Maximun	n Ratings			•	•
I <sub>S</sub>	Maximum Continuous Drain-Source Dio	de Forward Current			20	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				60	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 20A			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>S</sub> = 20A		450		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s   (Note 4)$		8.2		μС

#### NOTES

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I $_{AS}$  = 8A, V $_{DD}$  = 50V, R $_{G}$  = 25 $\Omega$ , Starting T $_{J}$  = 25 $^{\circ}$ C
- 3.  $I_{SD} \leq$  20A, di/dt  $\leq$  200A/ $\mu$ s,  $V_{DD} \leq$  BV $_{DSS}$ , Starting  $T_J$  = 25°C
- 4. Pulse Test: Pulse width  $\leq 300 \mu s, \, \text{Duty Cycle} \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

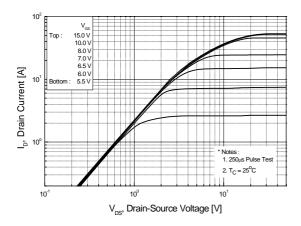


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

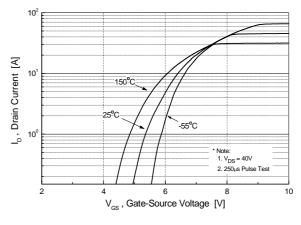
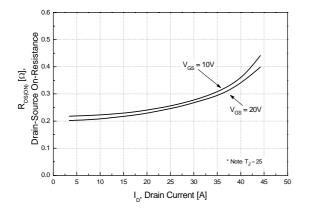
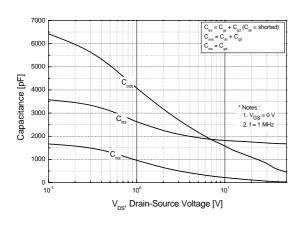


Figure 2. Transfer Characteristics

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue



**Figure 5. Capacitance Characteristics** 



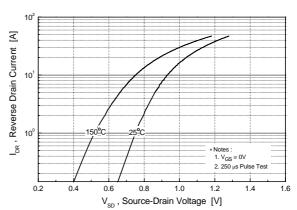
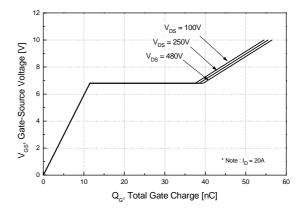


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

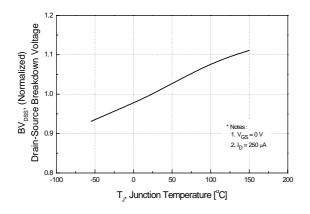


Figure 9. Maximum Safe Operating Area

Figure 8. On-Resistance Variation vs. Temperature

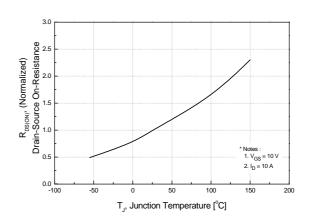


Figure 10. Maximum Drain Current vs. Case Temperature

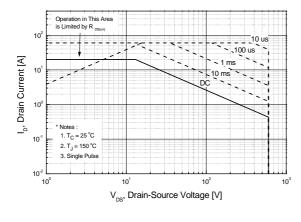
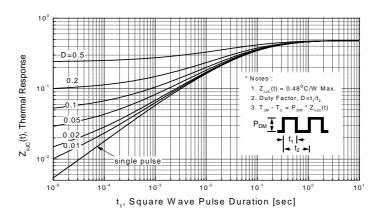
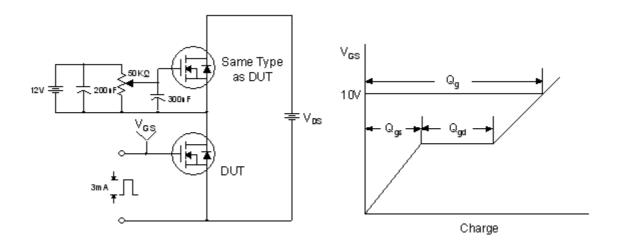


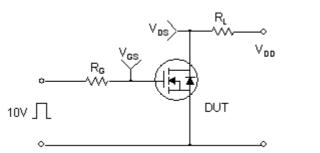
Figure 11. Transient Thermal Response Curve

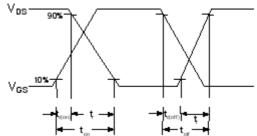


#### **Gate Charge Test Circuit & Waveform**

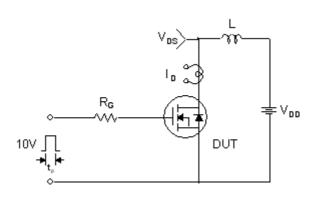


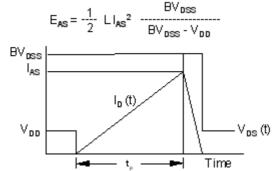
#### **Resistive Switching Test Circuit & Waveforms**



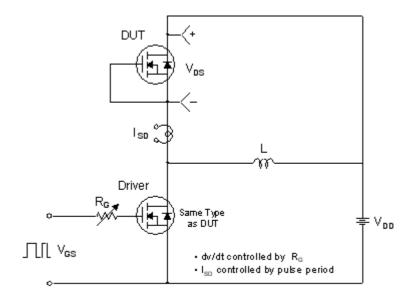


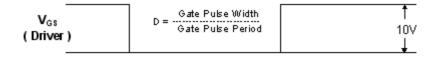
#### **Unclamped Inductive Switching Test Circuit & Waveforms**

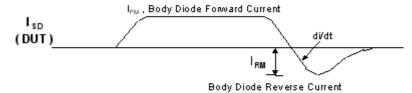


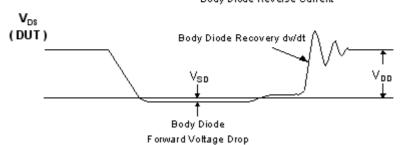


#### Peak Diode Recovery dv/dt Test Circuit & Waveforms



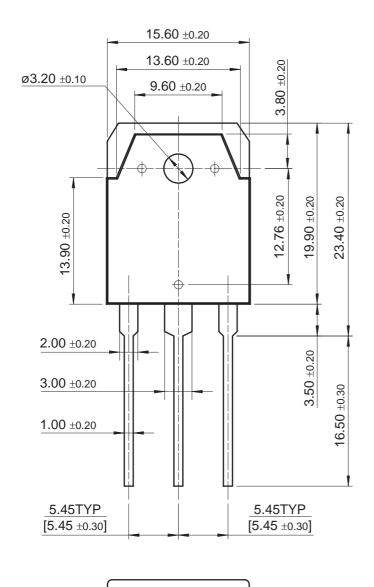


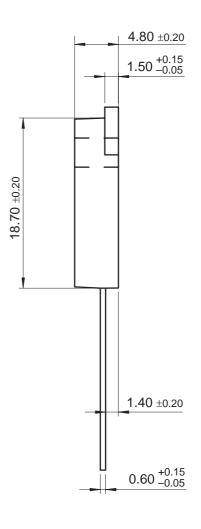




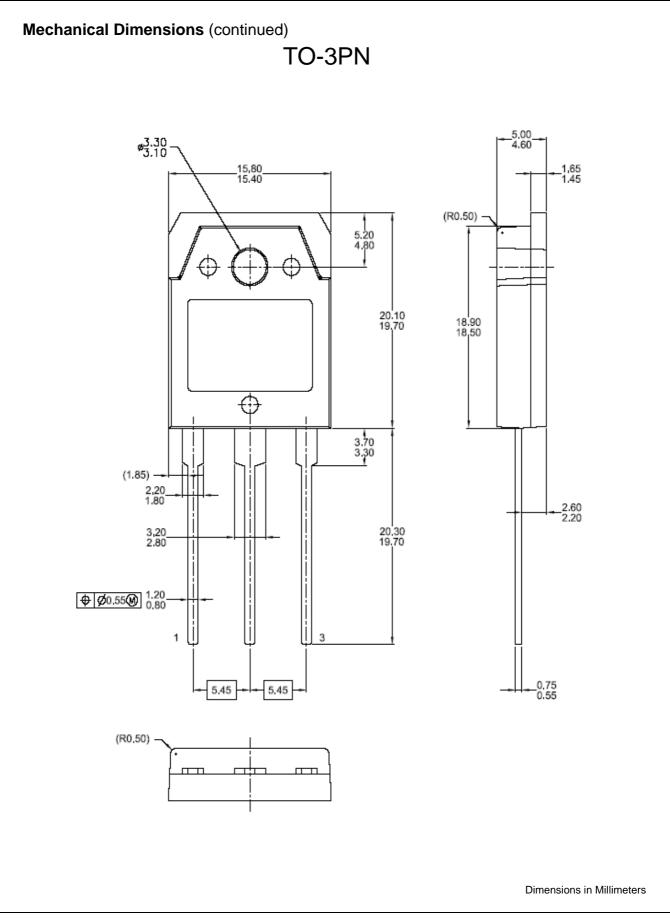
## **Mechanical Dimensions**

**TO-3P** 





Dimensions in Millimeters







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